

FORM PTO-1449

ATTY. DOCKET NO.  
20.2799SERIAL NO.  
10/065,303LIST OF INFORMATION PROVIDED  
BY APPLICANT

(Use several sheets if necessary)

APPLICANT:  
Michael Evans et al.FILING DATE: GROUP  
10/01/2002 2878

## REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Patentee
ANL	AA	4,945,233	07/31/90	Jorro
APK	AB	3,435,215	06/06/67	Pritchett
APC	AC	3,860,816	01/14/75	Wilson
APN	AD	4,085,323	04/18/78	Turcotte et al.
APM	AE	2,816,235	12/10/57	Scherbatkoy
	AF			
	AG			
	AH			
	AI			
	AJ			
	AK			
	AL			

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation
					Yes      No
	AM				
	AN				

## OTHER INFORMATION PROVIDED (AUTHOR, TITLE, DATE, PLACE OF PUBLICATION, PERTINENT PAGES, ETC.)

*an* AO Search Report from GB 0222688.4 dated June 10, 2003.

EXAMINER		DATE CONSIDERED
<i>an</i>		9/28/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.
2. This is not a representation that a search has been made.

# Electronic Information Disclosure Statement

## Multi-Point Subsurface Measurement Calibration

Application:

Confirmation:

Applicant(s): Michael Evans

Docket Number: 20.2799

Group Art Unit:

Examiner:

search string: ( 5459314 or 6389367 or 6289283 or 5699246 ).pn.

JC474 U.S. PRO  
10/065303  
10/01/02



### US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Citation No.	Patent Number	Date	Bar Code	Patentee	Class	Subclass
px	P01	5459314	1995-10-17		Plasek	/	/
px	P02	6389367	2002-05-14		Plasek	/	/
px	P03	6289283	2001-09-11		Plasek	/	/
px	P04	5699246	1997-12-16		Plasek	/	/

### Signature

Examiner Name	Date
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*[Handwritten signature]* 9/28/04